

# NAND Flash Solid State Storage Performance and Capability -- an In-depth Look

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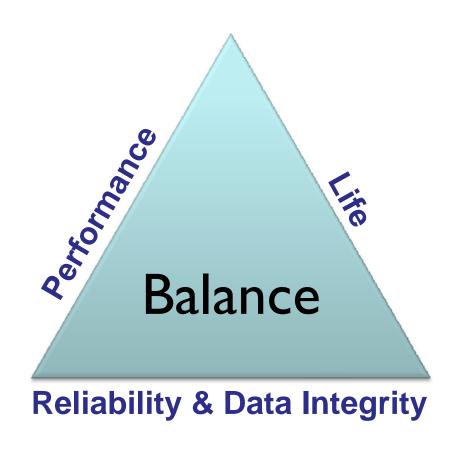
# **Abstract**



- NAND Flash Solid State Storage Performance and Capability
  - "This tutorial provides an in-depth examination of the fundamental theoretical performance, capabilities, and limitations of NAND Flash-based Solid State Storage (SSS). The tutorial will explore the raw performance capabilities of NAND Flash, and limitations to performance imposed by mitigation of reliability issues, interfaces, protocols, and technology types. Best practices for system integration of SSS will be discussed. Performance achievements will be reviewed for various products and applications. Several examples of successful enterprise deployments with comparative performance and cost-performance will be presented."

# **Data Integrity + Performance**





There can be no data integrity trade-off for performance

# Media Reliability / Availability



#### The GOOD:

- No moving parts
- Catastrophic device failures are rare (post infant mortality)

#### The BAD:

- Relatively high bit error rate, increasing with wear
  - MLC wear rate (higher capacity density) worse than SLC
  - > Higher density NAND Flash will increase bit error rate
- Program and Read Disturbs

#### The UGLY:

- Partial Page Programming
- Data retention is poor at high temperature
- Infant mortality is high (large number of parts...)

# **Controller Reliability Management**



- Wear leveling & Spare Capacity (e.g. Spare Blocks)
- Read & Program Disturb Controls
- Data & Index Protection
  - ECC Correction
  - Internal RAID
  - Data Integrity Field (DIF)
- Management

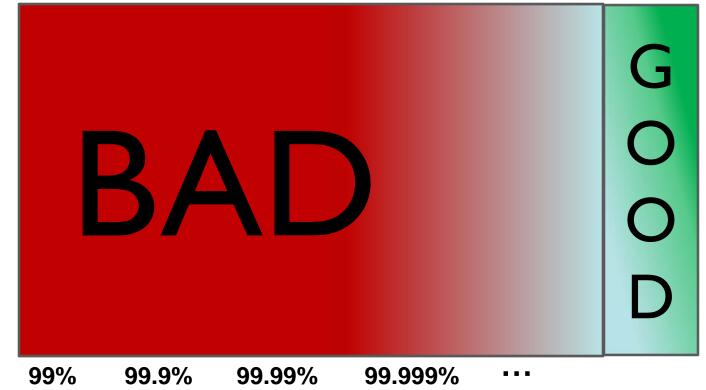
Poor Media + Great Controller -> Great SSS Solution

Note: Multipage Programming Should Not Be Done

# Data Integrity .V. Performance







Data Integrity

# Performance is about ROI



# ROI

# **Lower CapEx**

- Fewer CPUs
- Less RAM
- Less Network Gear
- Fewer SW Licenses
- Less Space

# Lower OpEx

- Less HW Maintenance
- Less SW Maintenance
- Greater Uptime
- Less Power/Cooling
- Fewer Diverse Skills

# **Higher Productivity**

# **SSS ROI: Three Quick Examples**



# Case Studies Wine.com Cloudmark

O&G

# Company: Wine.com



- On-line internet Retail
- Representative Markets:
  - Transaction Processing
  - Data Mining
- Problem
  - Systems not capable → Contract out data mining
  - Performance hitting 100%→ Loss of revenue (4Q07)
  - Cost to meet growth: prohibitive

### Wine.com



#### **Before (3Q2008)**

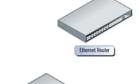
#### Internet

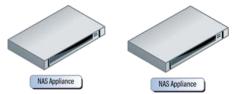


Back End Payment Processing

Front End







#### After (1Q2009)

#### Internet



Application level replication for redundancy



33% CapEx avoidance50% OpEx reduction33% Footprint reduction





12x improvement on write

- Latency down from 4 to <1ms

14x improvement on read

- Latency down from 12 to <1ms

"Enough capacity to cover 24 months of growth"

Geoffrey Smalling - CTO

# **Company: Cloudmark**



- Email Security Spam, Phishing, Viruses, etc.
- Protecting 850 Million mailboxes globally
  - 100+ Service Provider customers (mostly Tier-I)
  - High TPS at master morning bursts are higher
- Problem scaling MySQL & InnoDB worldwide
  - Rapid growth both customers and new threats
  - I/O limited → hit performance ceiling 50% of the time
  - Slave servers fall behind → increasing risk window
  - ◆ High transaction rate → constant disk failures
  - Cost to meet growth: prohibitive

# Cloudmark



- Transformed slave clusters to Solid State Storage and retired disk arrays – results:
  - 4 to I footprint reduction
  - CapEx avoidance \$2 million
  - 10x performance increase
  - Cluster peak utilization now only 15% of IOPS capability
  - 12 months growth secured with current hardware

"We never thought our problems would ever change from disk I/O problems to CPU bottlenecks!"

**Ryan White – Director of Operations** 

# **Company: LLOG**



- Oil & Gas exploration
- Market:
  - Natural resource discovery using seismic interpretation leading to production
  - Seismic analysis software used for 3D interpretations
    - Manipulation and analysis of large datasets (ITb+)
  - Quality interpretations result in accurate auction bids
    - > Minimize risk and make informed decisions
- Geoscientist productivity challenges
  - Idle time loading data into high-end workstations
  - Lost productivity during basic analysis tasks
  - Time wasted in running jobs in serial

# **LLOG**



- Use of Solid State Storage on workstations
  - Load time reduced from 8 to 2 minutes
  - 3D time slice time reduced from 28 to 18 minutes
- "Supercharged Virtualization" with Solid State Storage
  - Projects took 30+ minutes causing 100% CPU utilization
    - Now 10 minutes with projects run in parallel
  - Increased geoscientist's productivity 5x (projects in parallel)

"We are more competitive because we make better decisions and did it while reducing our costs"

John Hollins – Geophysicist



# Performance Matters



# Performance RO

### **Media Performance**



#### The GOOD:

- Performance is great (wrt HDDs)
- High performance/power (IOPS/Watt)
- Low pin count: shared command / data bus → good balance

#### The BAD:

- Not really a random access device
  - Block oriented
  - > Slow effective write (erase/transfer/program) latency
  - > R/W access speed imbalance
- Performance changes with wear
- Some controllers do read/modify/write
- Others use inefficient garbage collection

#### The UGLY:

Some controllers do read/erase/modify/write

# Performance Drivers – SSS Design



- Interconnect
- Number of NAND Flash Chips (Die)
- Number of Buses (Real / Pipelined)
- Data Protection (internal/external RAID; DIF; ECC...)
- SLC / MLC
- Effective Block (LBA; Sector) Size
- Write Amplification
- GC Efficiency
- Bandwidth Throttling
- Buffer Capacity & Mgmt

# Performance Drivers - External Cond SNIA

- Transfer Size
- Read/Write Ratios
- Temporal Randomness of Access
- Reserve Capacity Setting (% of used capacity)
- System Limitations (especially wrt scalability)
  - External Controller (#, Type, Performance); # Threads
  - CPU (#Cores, GHz)
  - System Bandwidth
  - Software Stack; Interrupt Handler
- External RAID
- Life of device (change in device affects tErase & tProgram)

# Simplified Theoretical Analysis



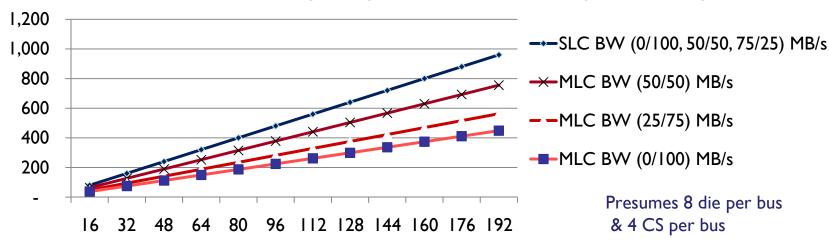
- Bandwidth Only (Not IOPS)
  - Large Transfers (Data length = Integer \* # die)
  - Infinite Buffer
  - Reads/Writes queued for maximum bandwidth
  - No system latency
- Read/Write Ratio %'s fixed
  - + 100/0, 75/25, 50/50, 25/75, 0/100
  - Steady State, 100% Efficient GC (EB erase / EB written = I)
- Maximum Total BW for SATA-II and PCI-e X4
  - No overhead considered
- SLC

# **Bandwidth Depends on # Die**



		SLC	MLC
Transfer Rate (MB/s)	tRC & tWC	400	400
Page Program (us)	tProgram	200	600
EB Erase (us)	tErase	3000	10,000
Load Page (us)	tR (tRead)	25	60
Capacity per die		0.5	1.0

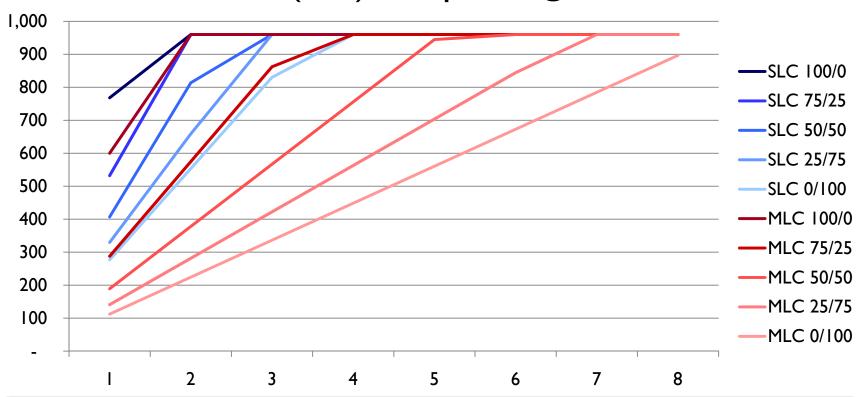
#### Theoretical BW (MB/s) v Number of Die (SLC, MLC)



# Single Layer Cell v Multi-Layer Cell



#### Bandwidth (MB/s) v #Chip Select @ R/W Ratio



Read / write performance imbalance closed with additional banks Greater R/W imblance in MLC requires more banks

# **Performance Data Acquisition**



- In this presentation, three commercially available SSS storage solutions were tested under a variety of conditions using a common system:
- Supermicro X7DWE Motherboard
  - Dual, Quad Core Intel X5460: 3.16 GHz
  - I6 GB DRAM
    - > 4x4GBKVR800D2D4F5 /4GI, 800MHz FBDIMM DDR2, CL5
  - PCI-E Gen 2 bus
- SATA Controller LSI SAS3081E-R
  - All tests except pathological write, which used on-board SATA
  - Driver version used was: 4.00.43.00; firmware rev: FwRev=011b0000h/

Note: all data collected on devices at beginning of life

# **Performance Data Acquisition**



#### Software / OS

- Linux/CentOS5/RHEL5 2.6.18-92.1.10.el5.
- "fio" program, version 1.21:
  - > From <a href="http://freshmeat.net/projects/fio">http://freshmeat.net/projects/fio</a>)
- "IOMeter" V 2006.07.27
  - > in Windows 2003/2008 for latency only

# Settings

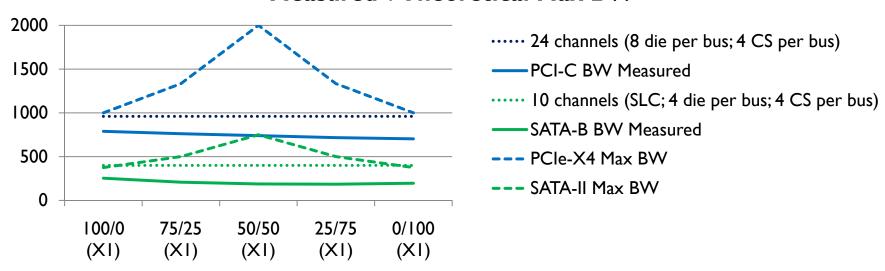
- Direct I/O: o\_direct used to bypass caching & buffering
- I/O Scheduler (elevator algorithm) set to null

Note: all data collected on devices at beginning of life

# **Measured v Theoretical Bandwidth**



#### Measured v Theoretical Max BW

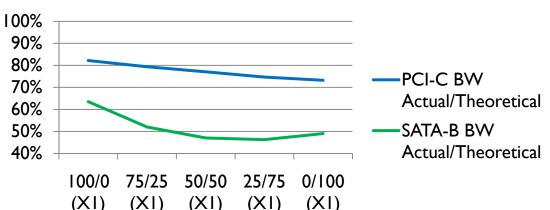


Note: Theoretical Max BW with 24 channels (4 die per bus, 4 CS per bus) is identical to the PCI-C, 24 channel shown in these charts.

Capacity Multiplier:

SATA-B: I PCI-C: 2

#### Measured BW as % of Theoretical Max



# **Product Specifications**



#### Features directly affecting performance measurements

	SATA (A)	SATA (B)	PCI (C)
Capacity (GB)	32	32	160
Bus/Link	SATA-II (3 Gb/s)	SATA-II (3 Gb/s)	PCI-E X4 I.I
Memory Type	SLC	SLC	SLC
Adjustable Reserve  Capacity	No	No	Yes
SSS Internal RAID Running during test	No N/A	No N/A	Yes Yes
K-IOPS (RMS)	8	27	88
K-IOPS (RMS) / WATT	3	?	7
Bandwidth (RMS, MB/s)	56	208	743
ECC correction	7 bits in 512B	?	II bits in 240B

# **Access Process (Physics Ignored)**



#### Read Access

- Address Chip / EB / Page
- Load Page into Register
- Transfer Data From Register I-byte per cycle

#### Typical NAND Flash Die:

- 2000 Erase Blocks (EB)
- 64 Pages per EB
- 4000 Bytes per Page
- 500 MByte Total Capacity
- 500 MByte Total Capacity
- 4000 Bytes per Page

#### Write Access

- Address Chip / EB
- Erase EB

...some time later...

- Address Chip / EB / Page
- Transfer Data To
   Register I-byte per cycle
- Program Register to Page

# **Example 1: Read/Erase/Modify/Write SNIA**



	Tin	ne = 1	tl			Tin	ne =	t2			Tir	ne =	t3	
	Starting State			Wr	Write Buffer & W,X,Y			Write	Buffe	er & Z	,A,B',	C',R'		
Page	Page Erase Blo		Block	k I	Page	E	rase l	Block		Page	E	rase	Block	
0	b	С			0	b	С	W	X	0	B'	C,	W	X
I	j		k	ı	I	j	Y	k	l	I	j	у	k	I
2	m				2	m				2	m	Z	Α	
3			P	r	3			P	r	3			q	R'
Buffer holds data while EB-1 Erased  Buffer holds while EB-1 E							3							
		Pa	ige	Era	se Blocl	k I		Page	E	rase Blo	ock I			
			0					0						

3

# **Explanation of Previous Slide**



#### Assumptions

- Simplified to show erase blocks with 4 pages, each page having 4 data blocks
- Invalid (erased or replaced) data is indicated by "—"
- Old data is indicated by lower case letters
- New data is indicated by CAPs; Replacement data is indicated by "prime" (e.g.  $c \rightarrow C$ )
- $\triangleright$  Detail T = t1 to T = t2 transition
  - Data is read from EB-I
  - EB-I is erased
  - New data {W,X,Y} modifies previous invalid data
  - Data is written back to EB-I
- $\triangleright$  Detail T = t2 to T = t3 transition
  - Data is read from EB-1 into data buffer
  - EB-I is erased
  - New data {B', C', Z, A, R'} modifies previous data in data buffer
  - Data is written back to EB-I

Note: backup material for those reviewing or looking at presentation without audio/video

# **Example 2: Read/Modify/Write**



#### Time = tI

Starting State

#### Time = t2

Data to Buffer (not shown)

Erase EB-I (not shown)

Write Buffer & W,X,Y to EB-I

#### Time = t3

Data to Buffer (not shown)

Erase EB-I (not shown)

Write Z,A & Replace b,c,r with B',C',R' & Write EB-I

Page	Erase Block I				
0	b	С			
1	j		k	I	
2	m				
3			q	r	

Page	Erase Block 2				
0	b	С	W	X	
I	j	Y	k	l	
2	m				
3			q	r	

Page	Erase Block 3				
0	B'	C,	W	X	
- 1	j	у	k	Ι	
2	m	Z	Α		
3			q	R'	

Implicit wear leveling; EB-1 → EB-2 → EB-3

Presumes that destination EB-2 & EB-3 erased prior to transfer of data → higher performance (than previous "Read/Erase/Modify/Write" example)

# "Write Amplification Impact"



- In this example,
  - Data written t1 to t2: 16 blocks
    - > NEW DATA {W, X, Y} 3 blocks; Copied Data {b, c, j, k, l, m, q, r} 8 blocks
    - > Null Data: 5 blocks
  - Data written t2 to t3: 16 blocks
    - NEW DATA {B', C', Z, A, R'} 5 blocks; Copied Data {w, x, j, y, k, l, m, q} 8 blocks
    - > Null Data: 3 blocks
  - (2) EB erasures
  - 25% (8 of 32) writes are user initiated
  - 75% (24 of 32) writes are internal data movement (overhead)

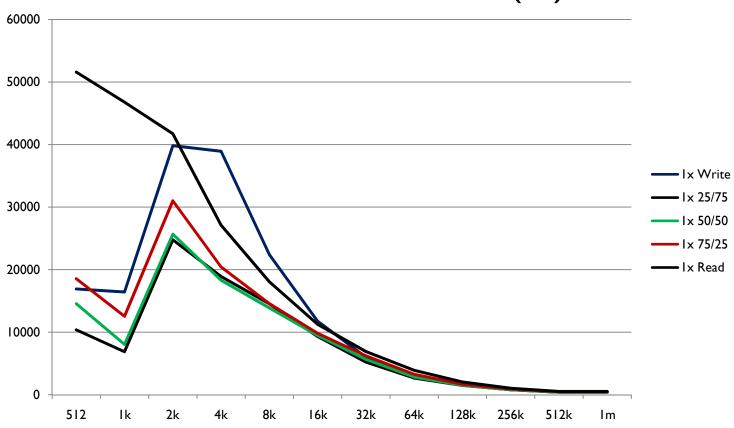
#### Important:

- Amount of valid or invalid data in EB-1 is irrelevant to performance impact
- "Write Amplification" is workload (access pattern) dependent (e.g., what if the write of R' above was not coincident with B' & C')

# **SATA-B: IOPS vs Transfer Size**



SATA-B: IOPS v Transfer Size (XI)



# **Example 3: Garbage Collection**



#### Time = tI

Start Garbage Collect EB-I

#### Time = t2

EB-I GC'd to EB-2 W,X,Y added

#### Time = t3

EB-I erase

b,c,r replaced by B',C',R'

Page	Erase Block I				
0	b	С			
- 1	j		k	Ι	
2	m				
3			q	r	

Page	Erase Block 2				
0					
I					
2					
3					

Page	Erase Block I				
0	þ	C			
I	j\	\	k	1	
2	m	\			
3	\	\ '	P	r	
	_	١.	1	2	

Page	Erase Block 2				
0	W	b	С	X	
I	Y	j	k	I	
2	m	q	r		
3					

Page	Erase Block I				
0					
I					
2					
3					

Page	Erase Block 2					
0	W			×		
I	у	j	k	I		
2	m	q		B'		
3	C,	Z	Α	R'		

# **Explanation of Previous Slide**



#### Assumptions

New data blocks and data blocks being garbage collected are interleaved

#### Details

- At Time = t0, erase block I (EB-I) is identified for GC
- At Time = t1, good data is moved from EB-1 to EB-2 (it is implicit that an index is updated accordingly); New data W, X, and Y are added while the GC is taking place. EB-1 is then ready to be erased
- At Time = t2, EB-2 is erased; Data for b, c, & r have been updated with B', C' & R'; b, c & r are indicated as "Invalid."

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# **GC Performance Impact**



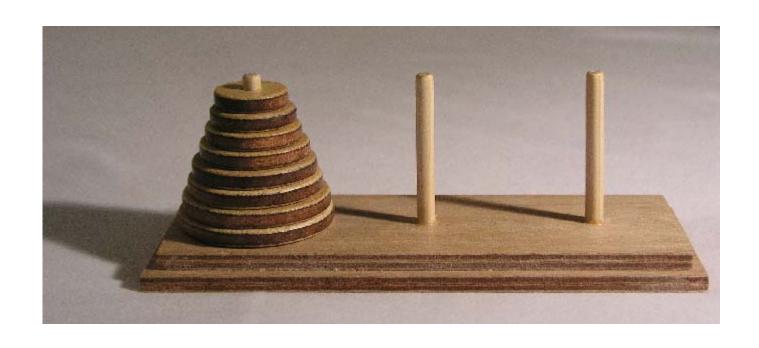
- In this example,
  - COPIED DATA: {b, c, j, k, l, m, q, r} 8 blocks
  - NEW DATA {W, X, Y, B', C', Z, A, R'} 8 blocks
  - 50% (8 of 16) writes are user initiated
  - 50% (8 of 16) writes are internal movement (overhead)

# Important:

- 50% of EB-I was "invalid data"
- What if only 10% had been "invalid data?"
- GC efficiency is dependent upon % of reserve capacity

### **Tower of Hanoi**





# Want to do this in fewer moves? Add more pegs!

# **GC: Pathological Write Conditions**



IF high percentage of total storage capacity utilized

### AND

High percentage of data has no correlation-in-time

### **AND**

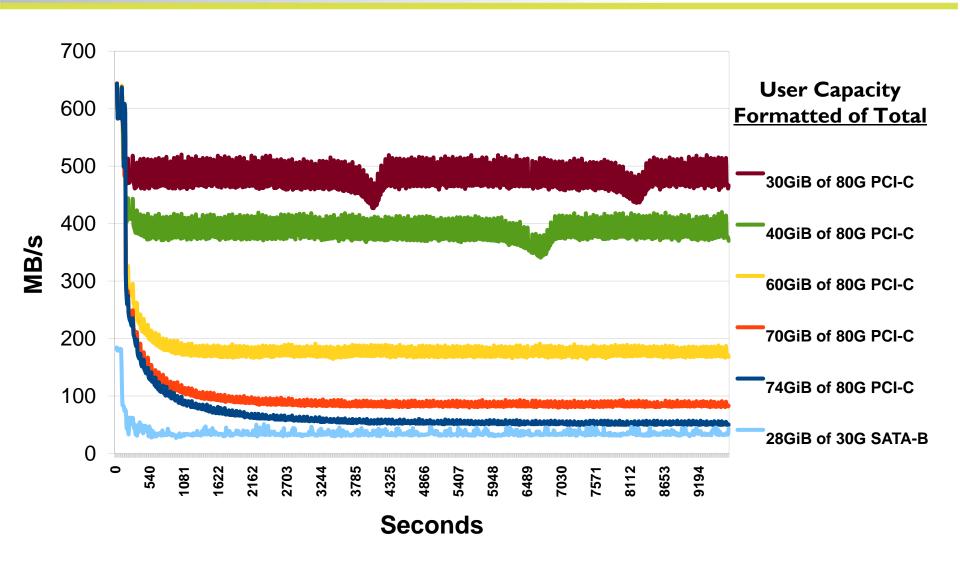
Continuous writing (no recovery time for GC)

### THEN

Efficiency of GC greatly diminished

### **Pathological Write Condition**





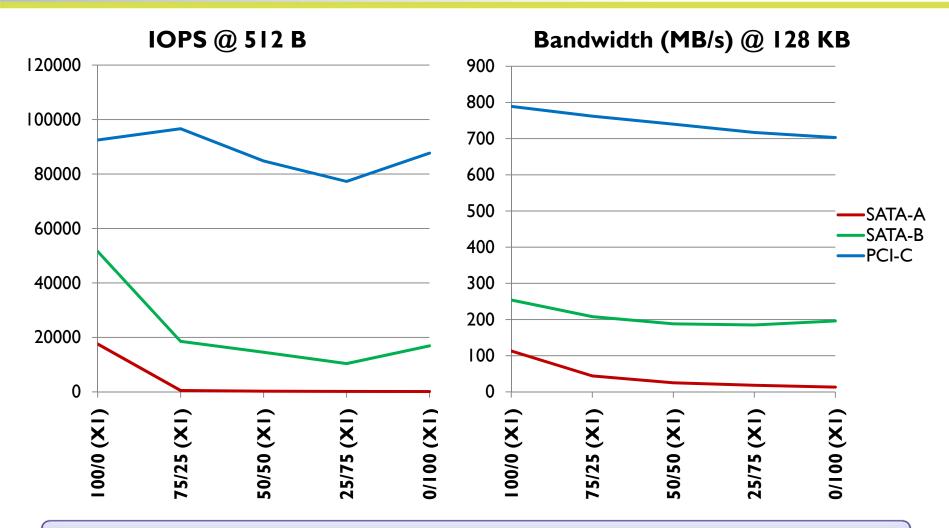
### **Scalability**



- Following Slides Show Scalability of {1, 2, 4, 8} units
  - Only I SATA controller is used limiting scalability
    - Only I thread running
- Measurements taken at Read/Write Ratios of
  - {100/0, 75/25, 50/50, 25/70, 0/100}
  - RMS value is the "root mean square" of these five values
- IOPS measurement taken at 512 Byte Transfers
- Bandwidth taken at 128K Byte Transfers
  - Unless shown differently
  - Linux has a 128K limit

### Performance v R/W Ratio

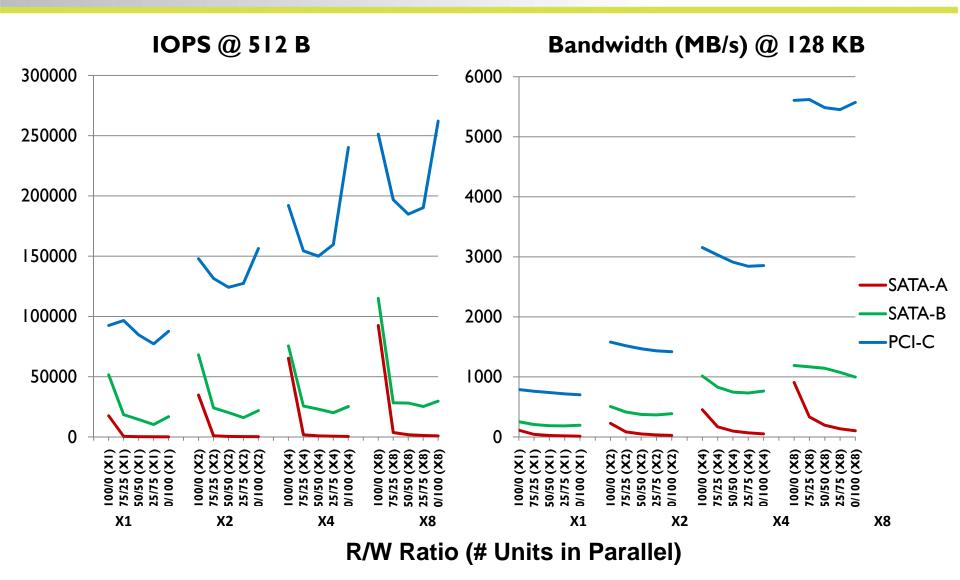




Read/Write Collisions -> Drop in Mixed Performance

### Scalability v R/W Ratio

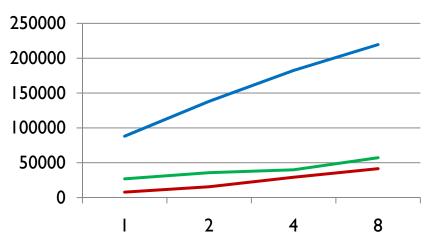




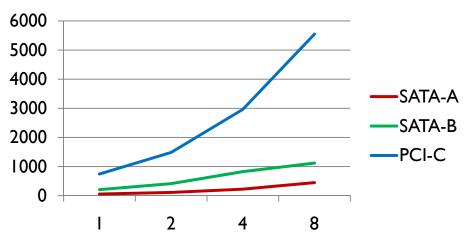
# RMS Scalability (# SSS Units)



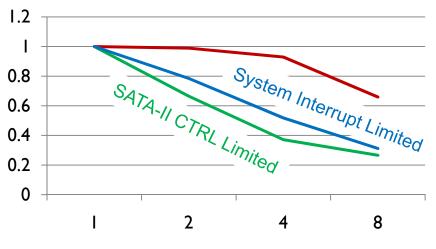




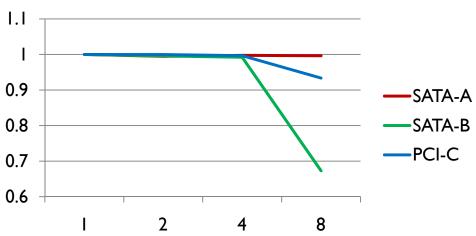
#### RMS of Bandwidth v Scale



#### Normalized RMS IOPS v Scale

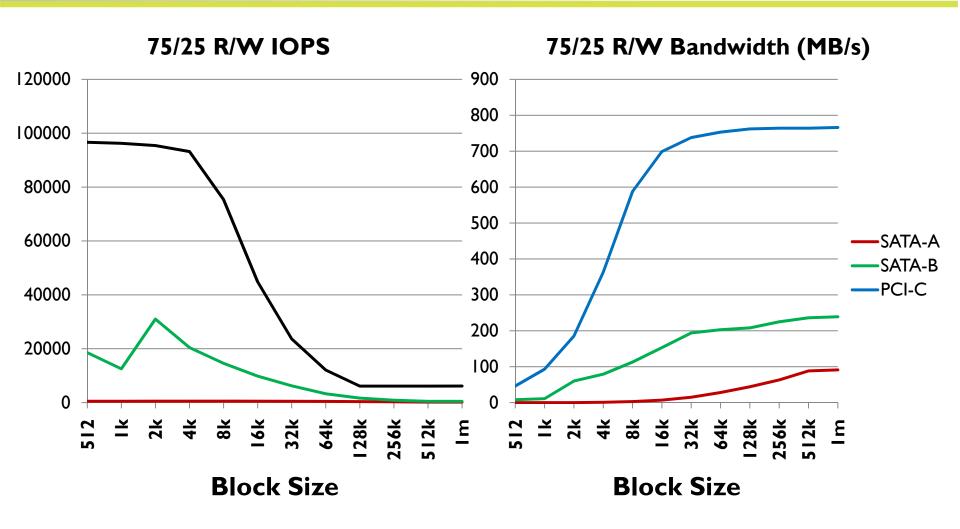


#### Normalized RMS Bandwidth v Scale



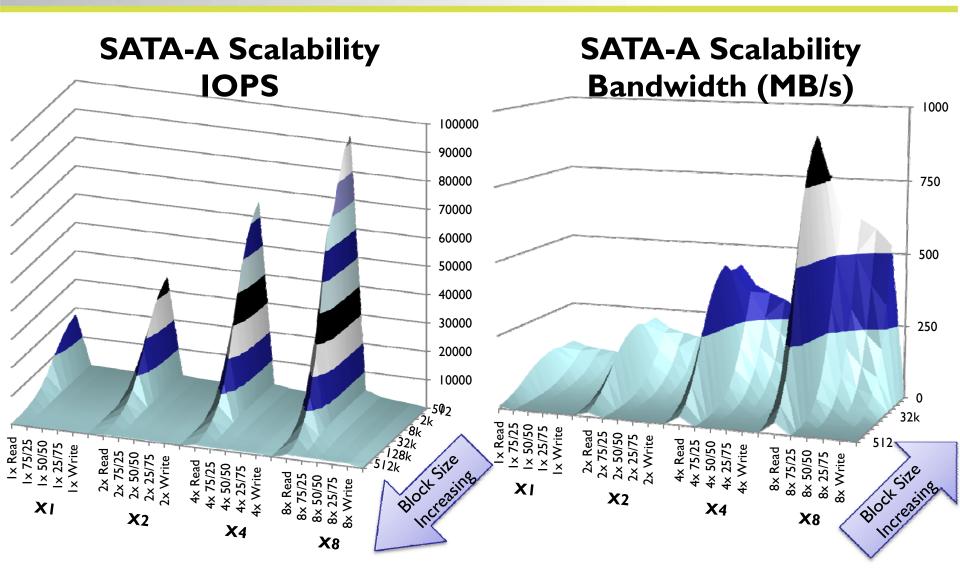
# Performance v Block Size (75/25)





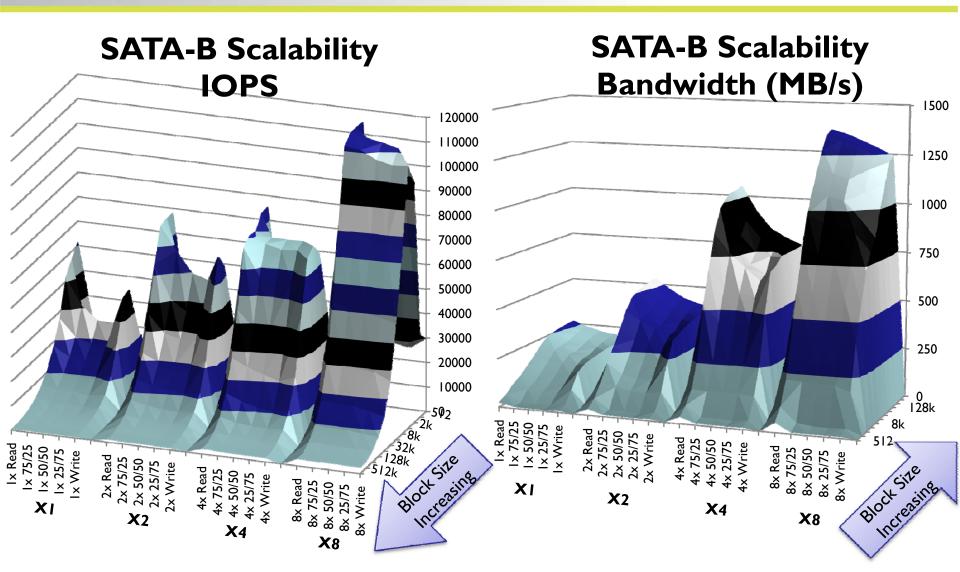
### Scalability v RW Ratio v Block Size





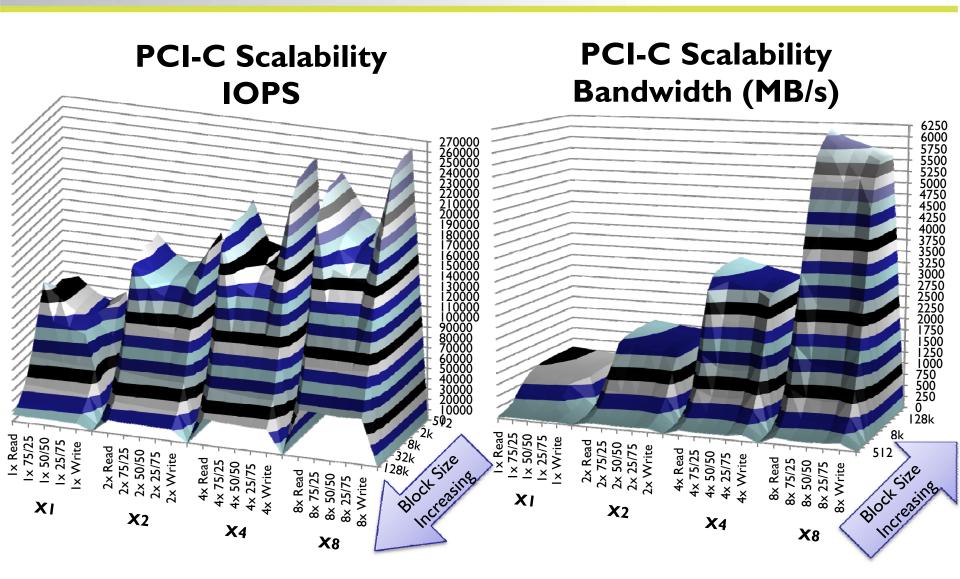
# Scalability v RW Ratio v Block Size





### Scalability v RW Ratio v Block Size





# **Media Reliability / Availability**



Problem	SSS Solution	System Solution
High Infant Mortality	RAID: NAND Flash	RAID: SSS
High Error Rate & Wearout	RAID: NAND Flash	RAID: SSS
	Robust ECC	No Defragmentation
	DIF	DIF
	Wear Leveling	Access Tuning
	Never Multi-page PGM	
	Thermal Management	Temperature & Air Flow
Non-random	Address Indirection	N/A
R/W not symmetric	More Banks (CS); esp for MLC	Reduce write thrashing

### **System Level Considerations**



- Data / Index Protection (DIF; RAID)
- Scalability
- Compare system- or data-center-level; not device
- Best case: test on real application, not benchmark
  - Plan to do tuning to reach top performance / objectives
  - Applications may have contra-indicated optimizations
    - > Example: keeping data in close physical proximity (short stroking)
    - > Example: caching algorithms

### **Questions to Ask: Things to Know**



### Bandwidth / IOPS at

- Block size(s) you need
- R/W ratio you use
- Steady State / Burst
- Data's temporal relationship
- Scalability
- RAIDing
- Reserve capacity used
- BOL / EOL

# **Questions to Ask: Things to Know**



- Design impacts on data integrity; life; failures & performance
  - ECC robustness
  - Write amplification / GC efficiency
  - Internal RAID
  - Bandwidth throttling
  - Partial Page Programming
- Test Conditions
  - RAID On/Off during testing?
  - Caching On/Off during testing?
  - Workload
  - Temporal Relationships
  - User capacity / reserve capacity

### **Q&A / Feedback**



Please send any questions or comments on this presentation to SNIA: <a href="mailto:tracksolidstate@snia.org">tracksolidstate@snia.org</a>

Many thanks to the following individuals for their contributions to this tutorial.

- SNIA Education Committee

Khaled Amer Phil Mills Rob Peglar Marius Tudor